Supplementary Information for

Detection and role of trace impurities in high-performance organic solar cells

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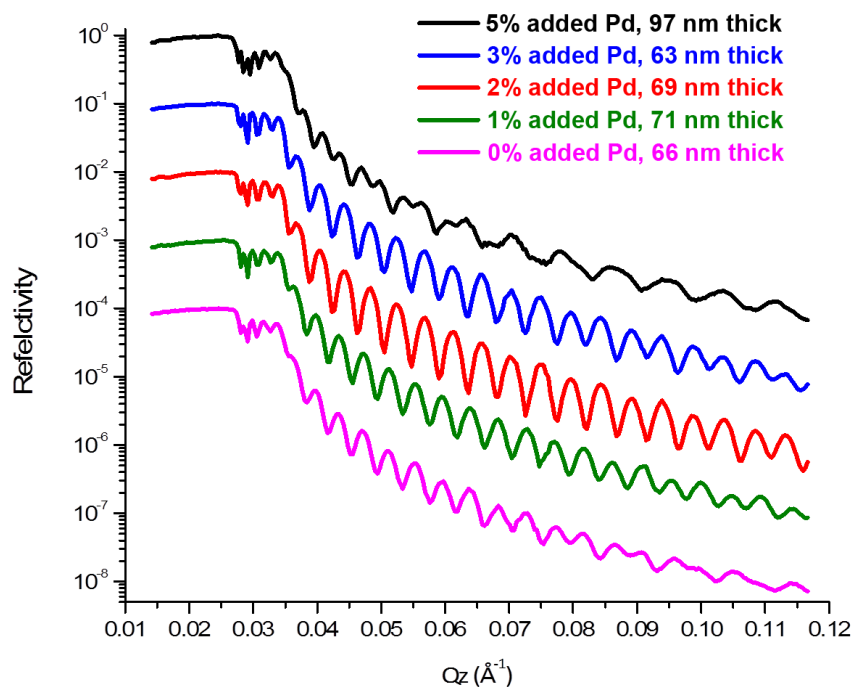
Figure S1. X-ray reflectivity (XRR) data from PTB7/PC$_{71}$BM blend films used in XRF

measurements having various amounts of added Pd(PPh$_3$)$_4$ catalyst.
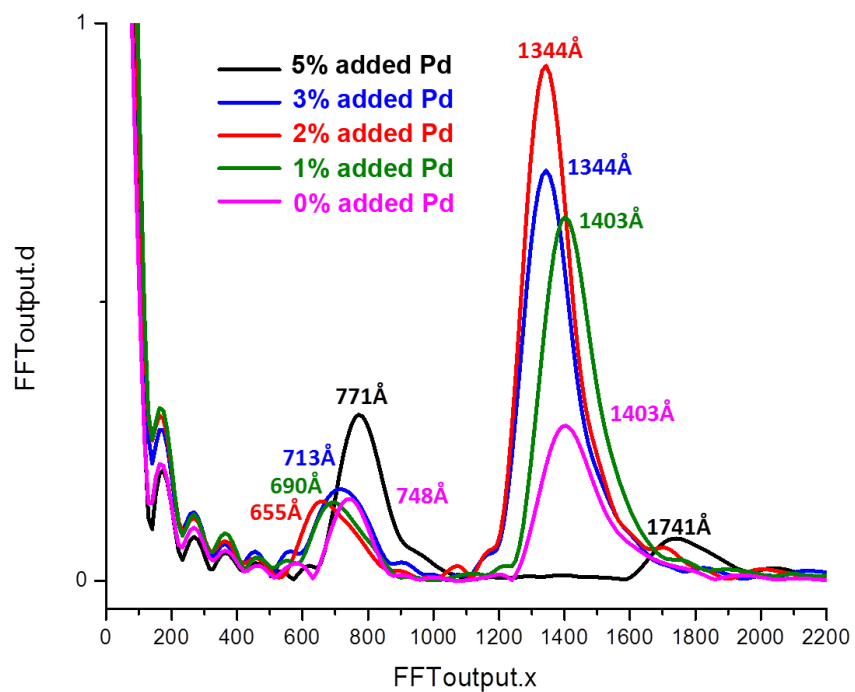
Figure S2. Fourier analysis of XRR data from PTB7/PC$_{71}$BM blend films used in XRF measurements having various amounts of added Pd(PPh$_3$)$_4$ catalyst. These FFT signatures were used to measure the film thickness.